



General Description

The WSP11N10T is the highest performance trench Dual N-Ch MOSFET with extreme high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The WSF11N10T meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

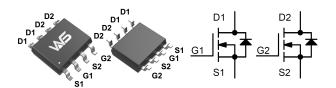
Product Summery

BVDSS	RDSON	ID
100V	70mΩ	12A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

SOP-8 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	100	V
V _{GS}	Gate-Source Voltage	±20	V
I _D @T _C =25℃	Continuous Drain Current, V _{GS} @ 10V ¹	12	Α
I _D @T _C =100℃	C Continuous Drain Current, V _{GS} @ 10V ¹ 6.0		Α
I _{DM}	Pulsed Drain Current ²		Α
EAS	EAS Single Pulse Avalanche Energy ³		mJ
I _{AS}	Avalanche Current	5	Α
P _D @T _A =25℃	P _D @T _A =25℃ Total Power Dissipation ⁴ 1.		W
T _{STG}	T _{STG} Storage Temperature Range -55 to 150 T _J Operating Junction Temperature Range -55 to 150		°C
TJ			$^{\circ}$

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
$R_{ heta JA}$	Thermal Resistance Junction-ambient ¹		85	°C/W
$R_{ heta JC}$	Thermal Resistance Junction-Case ¹		62	°C/W



N-Ch MOSFET

Electrical Characteristics (T_J=25 ℃, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	100			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25°C , I _D =1mA		0.098		V/°C
В	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =5A		70	95	0
R _{DS(ON)}	Static Dialii-Source Off-Resistance	V _{GS} =4.5V , I _D =3A		80	115	mΩ
$V_{GS(th)}$	Gate Threshold Voltage)/ -\/ -250\	1.2	1.8	2.5	٧
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=250uA$		-5.52		mV/℃
	Drain Source Leakage Current	V _{DS} =100V , V _{GS} =0V , T _J =25℃			1	
I _{DSS}	Drain-Source Leakage Current	V _{DS} =100V , V _{GS} =0V , T _J =55℃			100	- uA
I _{GSS}	Gate-Source Leakage Current	V_{GS} = $\pm 20 V$, V_{DS} = $0 V$			±100	nA
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		3.0		Ω
Q_g	Total Gate Charge (10V)			12		
Q_gs	Gate-Source Charge	V _{DS} =50V , V _{GS} =10V , I _D =10A		2.9		nC
Q_{gd}	Gate-Drain Charge			1.5		
$T_{d(on)}$	Turn-On Delay Time			11.8		
T _r	Rise Time	V _{DD} =50V , V _{GEN} =10V ,		3.1		no
$T_{d(off)}$	Turn-Off Delay Time	$R_G=6\Omega I_D=1A$, $R_L=30\Omega$		15		ns ns
T_f	Fall Time			4.5		
Ciss	Input Capacitance			1055		
C _{oss}	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		58		pF
C _{rss}	Reverse Transfer Capacitance			42		

Guaranteed Avalanche Characteristics

	Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ı	EAS	Single Pulse Avalanche Energy ⁵	V _{DD} =50V , L=0.5mH , I _{AS} =5A	3			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,6}	V _G =V _D =0V , Force Current			11	Α
I _{SM}	Pulsed Source Current ^{2,6}				30	Α
V_{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =5A , T _J =25℃			1.1	V
t _{rr}	Reverse Recovery Time	lF=5A , dl/dt=100A/μs , T J=25℃		21		nS
Q _{rr}	Reverse Recovery Charge			25		nC

Note:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper,t<10sec.
- 2.The data tested by pulsed , pulse width $\leqq 300 us$, duty cycle $\leqq 2\%$
- 3. The EAS data shows Max. rating . The test condition is V_{DD} =50V, V_{GS} =10V, L=0.5mH, I_{AS} =5A
- 4. The power dissipation is limited by 150 ℃ junction temperature
- 5. The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



N-Ch MOSFET

Typical Characteristics

ls Source Current(A)

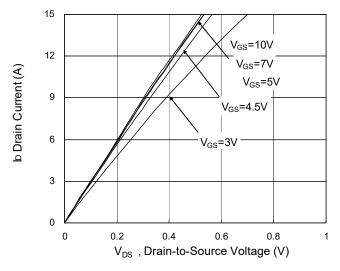


Fig.1 Typical Output Characteristics

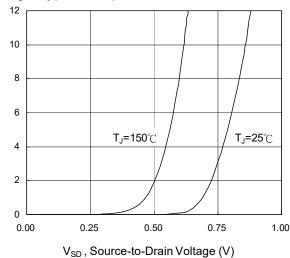


Fig.3 Forward Characteristics Of Reverse

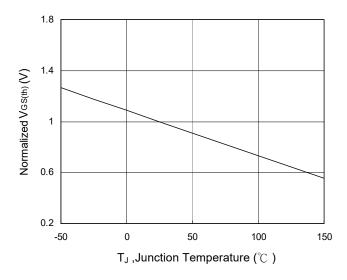


Fig.5 Normalized $V_{\text{GS}(\text{th})}$ vs. T_{J}

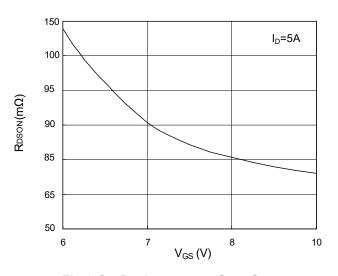


Fig.2 On-Resistance vs. Gate-Source

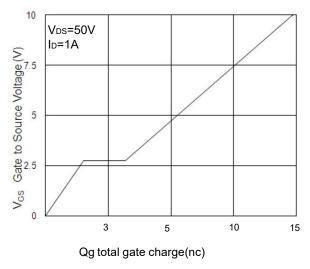


Fig.4 Gate-Charge Characteristics

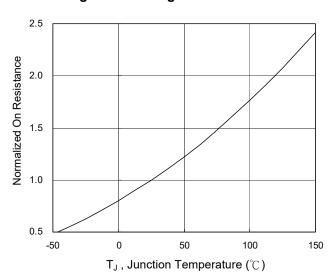
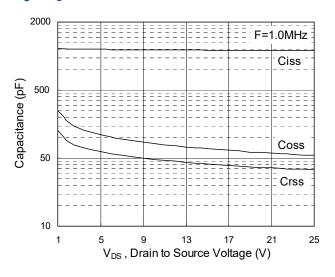


Fig.6 Normalized R_{DSON} vs. T_J



N-Ch MOSFET



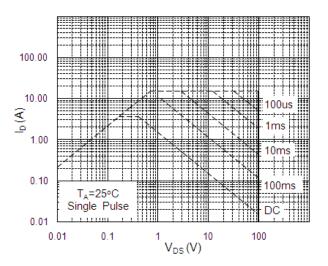


Fig.7 Capacitance

Fig.8 Safe Operating Area

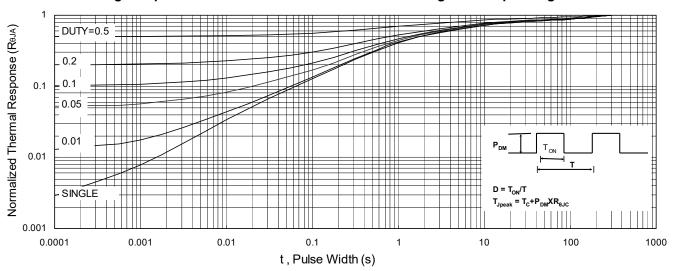


Fig.9 Normalized Maximum Transient Thermal Impedance

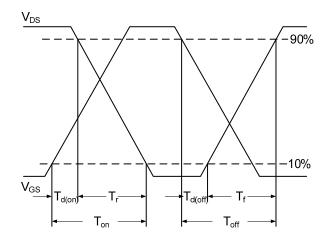


Fig.10 Switching Time Waveform

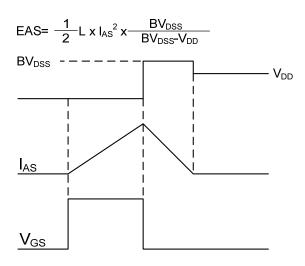


Fig.11 Unclamped Inductive Switching Waveform



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